

100V N-Channel Trench MOSFET(Preliminary)

General Description

- Trench Power Technology
- Low R_{DS(ON)}
- Low Gate Charge
- Optimized for fast-switching Applications

Applications

- Synchronous Rectification in DC/DC and AC/DC Converters
- Isolated DC/DC Converters in Telecom and Industrial

Product Summary

VDS 100V

 I_D (at V_{GS} =10V) 60A

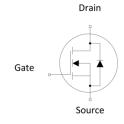
 $R_{DS(ON)}$ (at V_{GS} =10V) < 16.5m Ω

 $R_{DS(ON)}$ (at V_{GS} =4.5V) < 17.5m Ω

100% UIS Tested







Device	Package	Form	Marking
TTP60N10AT	TO-220	Tube	60N10AT

Absolute Maximum Ratings (T _A =25°C unless otherwise noted)						
Parameter		Symbol	Maximum	Units		
Drain-Source Voltage		V _{DS}	100	V		
Gate-Source Voltage		V _{GS}	±20	V		
Continuous Dunin Comment B	$T_{\rm C} = 25^{\rm o}{\rm C}$		60			
Continuous Drain Current ^B	$T_{\rm C} = 100^{\rm o}{\rm C}$	I _D	48	A		
Pulsed Drain Current A		I _{DM}	180	А		
Avalanche Current A		I _{AS}	30	А		
Single Pulse Avalanche Energy L =0.3mH ^A		E _{AS}	135	mJ		
Device Dissination C	$T_{\rm C} = 25^{\rm o}{\rm C}$	D	142	W		
Power Dissipation ^C	$T_{\rm C} = 100^{\rm o}{\rm C}$	P_{D}	47.6	W		
Operating Junction and Storage Temperature Range		T _J , T _{SGT}	-55 to 175	∘C		

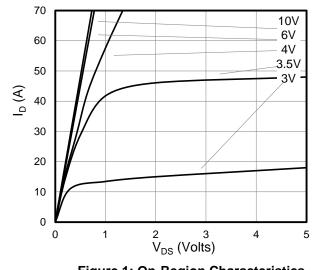
Thermal Resistance					
Parameter		Symbol	Maximum	Units	
Thermal Resistance, Junction-to-Case Steady-State		R _{thJC}	1.05	°C/W	
Thermal Resistance, Junction-to-Ambient	Steady-State	R _{thJA}	100	°C/VV	

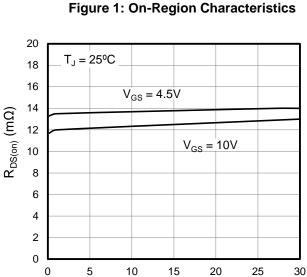


Electric	cal Characteristics(T _J =25°C ur	nless otherwise n	oted)				
0	Parameter		Value				
Symbol		Conditions		Min	Тур	Max	Units
STATIC P	ARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$		100			V
	Zara Cata Valtaga Prain Current	$V_{DS} = 100V, V_{GS} = 0V$ $T_{J} = 25^{\circ}C$ $T_{J} = 100^{\circ}C$	T _J =25°C			1	
I _{DSS}	Zero Gate Voltage Drain Current		T _J =100°C			25	μA
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$				±100	nA
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		1.0	1.5	2.4	V
R _{DS(ON)} Static Di		V _{GS} = 10V, I _D = 30A			12.5	16.5	mΩ
	Static Drain-Source On-Resistance	$V_{GS} = 4.5V, I_D = 30A$			13.5	17.5	mΩ
g _{FS}	Forward Transconductance	$V_{DS} = 5V, I_{D} = 20A$		47			S
V _{SD}	Diode Forward Voltage	I _S = 20A, V _{GS} = 0V				1	V
I _S	Maximum Body-Diode Continuous Current B					60	Α
DYNAMIC	PARAMETERS						
C _{iss}	Input Capacitance				8491		
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 50V, f = 1MH_Z$			206		pF
C _{rss}	Reverse Transfer Capacitance				175		
SWITCHI	NG PARAMETERS	•				•	
Q _g (10V)	Total Gate Charge		$V_{GS} = 10V, V_{DS} = 50V, I_D = 30A$		150		
Q_{gs}	Gate Source Charge	$V_{GS} = 10V, V_{DS} = 50V,$			20		nC
Q_{gd}	Gate Drain Charge				22		
t _{D(on)}	Turn-On Delay Time	$V_{GS} = 10V, V_{DS} = 50V, I_{D} = 30A,$ $R_{G} = 2.5\Omega$			17		
t _r	Turn-On Rise Time				14		
$T_{D(off)}$	Turn-Off Delay Time				56		ns
t _f	Turn-Off Fall Time				18		
t _{rr}	Body Diode Reverse Recovery Time				35		ns
Q _{rr}	Body Diode Reverse Recovery Charge	I _F = 30A, di/dt =100A/μs			58		nC

- A. Single pulse width limited by maximum junction temperature.
- B. The maximum current rating is package limited.
- C. The power dissipation P_D is based on $T_{J(MAX)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted





 $I_{D}\left(A\right)$ Figure 3: On-Resistance vs. Drain Current

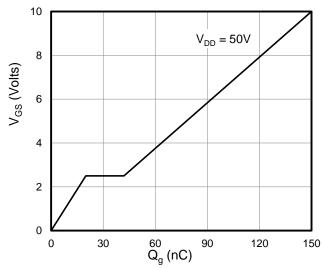


Figure 5: Gate Charge Characteristics

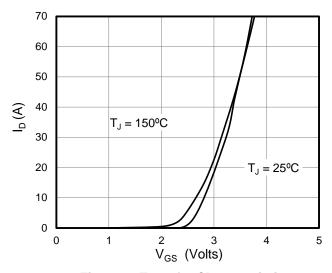


Figure 2: Transfer Characteristics

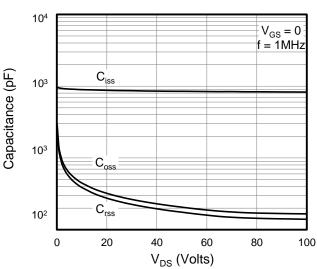


Figure 4: Capacitance Characteristics

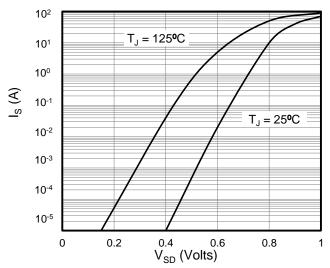
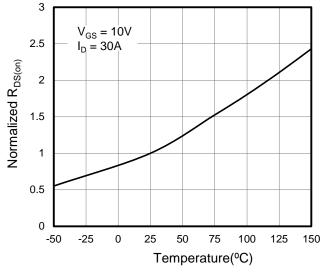


Figure 6: Body Diode Forward Voltage

Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted



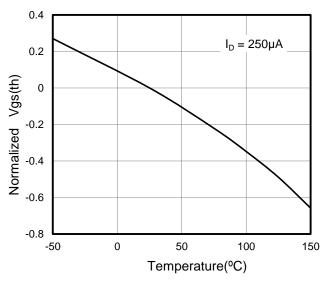
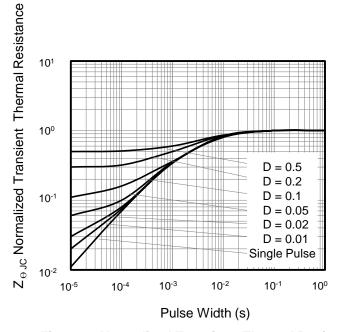


Figure 7: On-Resistance vs. Junction Temperature

Figure 8: Vgs(th) vs. Junction Temperature



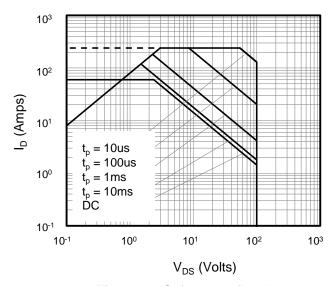


Figure 9: Normalized Transient Thermal Resistance

Figure 10: Safe Operating Area



Figure A: Gate Charge Test Circuit and Waveform

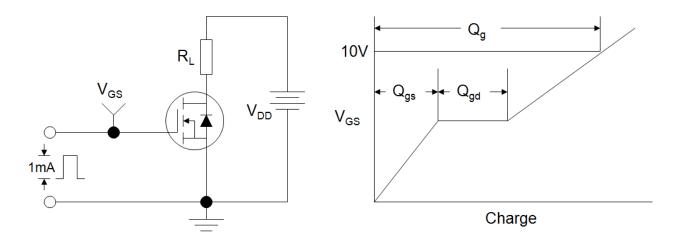


Figure B: Resistive Switching Test Circuit and Waveform

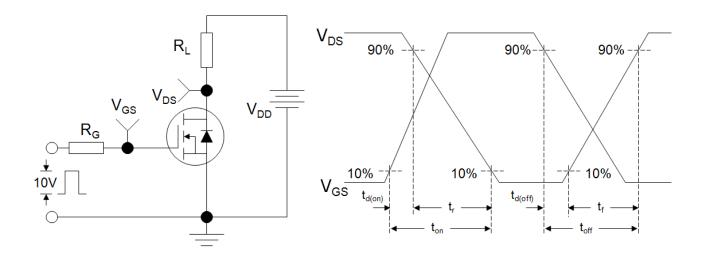
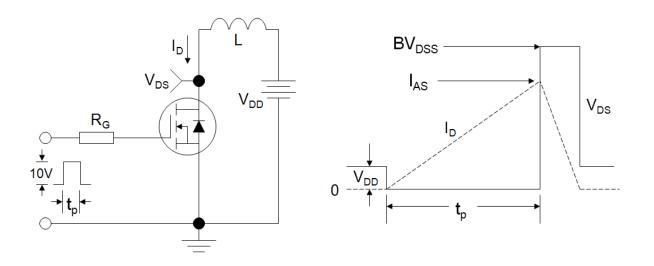
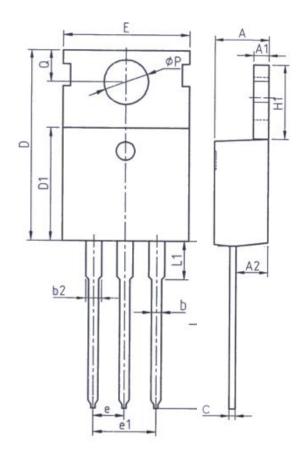


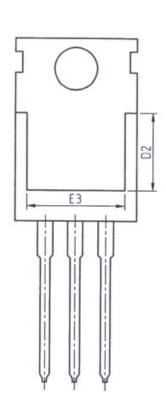
Figure C: Unclamped Inductive Switching Test Circuit and Waveform





TO-220





Unit: mm					
Symbol	Min.	Max.			
Α	4. 37	4. 77			
A1	1. 25	1. 45			
A2	2. 20	2. 60			
b	0. 70	0. 95			
b2	1. 17	1. 47			
С	0. 40	0. 65			
D	15. 10	16. 10			
D1	8. 80	9. 40			
D2	5. 50	_			

Unit: mm				
Symbol	Min. Max.			
E	9. 70	10. 30		
E3	7. 00	ı		
е	2. 54BSC			
e1	5. 08BSC			
H1	6. 25	6. 85		
L	12. 75	13.80		
L1	_	3. 40		
P	3. 40 3. 80			
Q	2. 60 3. 00			



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